Examiner-Initiated Interview Summary	Application No.	Applicant(s)
	10/586,748	HANGAI ET AL.
	Examiner	Art Unit
	DEAN O. TAKAOKA	2817
All Participants:	Status of Application:	
(1) <u>DEAN O. TAKAOKA</u> .	(3)	
(2) <u>ALI M. IMAM</u> .	(4)	
Date of Interview: <u>11 September 2009</u>	Time:	
Type of Interview:		
Part I.		
Rejection(s) discussed: 35 U.S.C. 102		
Claims discussed: 1,4,9,11,12		
Prior art documents discussed: Hieda		
Part II.		
SUBSTANCE OF INTERVIEW DESCRIBING THE GENERAL NATURE OF WHAT WAS DISCUSSED: See Continuation Sheet		
Part III.		
 It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview directly resulted in the allowance of the application. The examiner will provide a written summary of the substance of the interview in the Notice of Allowability. It is not necessary for applicant to provide a separate record of the substance of the interview, since the interview did not result in resolution of all issues. A brief summary by the examiner appears in Part II above. 		
(A ₁	pplicant/Applicant's Representat	ive Signature – if appropriate)

Continuation of Substance of Interview including description of the general nature of what was discussed: Applicant's amendment dated August 27, 2009 overcame the prior art of record however it was the position of the Examiner that amendments to claim 9 did not appear to overcome newly cited prior art of Hieda. In particular, Hieda (Fig. 5) shows parallel connected FET switches each comprising an inductor and connected to each otther thru intermediate switch 2a. Fig. 11 shows a SPDT switch. It was the position of the Examiner that dependent claim 10 would allowable comprising similar limitations of the parallel inductor connected to the series circuit of FET and capacitor also included in claim 4. It was agreed to combine claims 9 and 10 by Examiners amendment to place the claims in condition for allowance.